

Form PTO-1449

(MODIFIED)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

039153-298 (F0785)

SERIAL NO.

09/819,343

APPLICANT

Calvin T. Gabriel et al.

FILING DATE

03/28/2001

GROUP ART UNIT

1746

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
LS	A1	6,232,048	5/15/2001	Buynoski et al.	430	328	
LS	A2	6,197,687	3/6/01	Buynoski	438	328	671.
LS	A3	6,110,837	8/29/00	Linliu et al.	438	723	
LS	A4	5,876,903	3/2/99	Ng et al.	420	313	
LS	A5	5,468,595	11/21/95	Livesay	420	296	
LS	A6	3,997,367	12/14/1976	Yau	148	15	

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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LS [signature]

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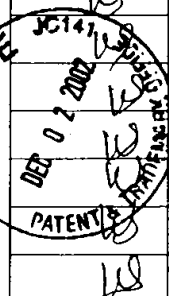
4/30/03

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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				APPLICANT Calvin T. Gabriel et al.				
				FILING DATE 03/28/2001		GROUP ART UNIT 1746		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE	
WJ	A1	6,197,687	3/06/2001	Buynoski	478	671		
WJ	A2	5,994,225	11/30/99	Liu et al.	478	313		
WJ	A3	5,876,903	3/02/99	Ng et al.	478	296		
WJ	A4	5,468,595	11/21/1995	Livesay	478	296		
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
WJ	A5	Chiong K.G. et al. "Resist Contrast Enhancement in High Resolution Electron Beam Lithography", Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, vol. 7, no. 6.						
WJ	A6	Patent Abstracts of Japan, vol 1999, no. 09, 30 July 1999 (1999-07-30) & JP 11 097328 A (Toshiba Corp), 9 April 1999 (1999-04-09) abstract						
EXAMINER WJ Weger				DATE CONSIDERED 4/20/03.				
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		APPLICANT Calvin T. Gabriel et al.	
		FILING DATE 03/28/2001	GROUP ART UNIT 1746

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	A1	6,420,097	07/16/2002	Pike et al.	430	313	
	A2	6,395,447	05/28/2002	Ishii et al.	430	191	
	A3	6,358,670	03/19/2002	Wong et al.	430	296	
	A4	6,319,655	11/20/2001	Wong et al.	430	311	
	A5	6,174,818	01/16/2201	Tao et al.	438	733	
	A6	4,446,222	05/01/1984	Kress	430	307	
	A7	4394,211	07/19/1983	Uchiyama et al.	156	628	

FOREIGN PATENT DOCUMENTS

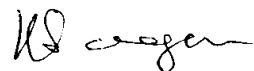
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							YES	NO

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